

# C. C. Chang

## Articles, Patents & PhD Thesis abstracts

### PhD Thesis ([abstract](#))

<http://adsabs.harvard.edu/abs/1967PhDT.....55C>

(Low Energy Electron Diffraction Studies, Adsorption of Oxygen, Carbon-Monoxide and Nitrogen on the Tungsten (112) Face.)

### Patents

<http://www.google.com/patents?hl=en&lr=&vid=USPAT4324038&id=-ko5AAAAEBAJ&oi=fnd&dq=Chuan+C.+>

[+Chang&printsec=abstract#v=onepage&q=Chuan%20C.%20%20Chang&f=false](#)

(Method of fabricating MOS field effect transistors)

<http://www.google.com/patents?>

[hl=en&lr=&vid=USPAT4623912&id=efl2AAAAEBAJ&oi=fnd&dq=Chuan+C.+](#)

[+Chang&printsec=abstract#v=onepage&q=Chuan%20C.%20%20Chang&f=false](#)

(Nitrided silicon dioxide layers for semiconductor integrated circuits)

### Low Energy Electron Diffraction

[http://rsi.aip.org/resource/1/rsinak/v42/i2/p189\\_s1?isAuthorized=no](http://rsi.aip.org/resource/1/rsinak/v42/i2/p189_s1?isAuthorized=no)

(LEED Optics as Electron Mirror Microscope)

[http://jap.aip.org/resource/1/japiau/v39/i12/p5570\\_s1?isAuthorized=no](http://jap.aip.org/resource/1/japiau/v39/i12/p5570_s1?isAuthorized=no)

(LEED Studies of the (0001) Face of  $\alpha$ -Alumina)

<http://scitation.aip.org/vsearch/servlet/VerityServlet?>

[KEY=FREEER&smode=results&maxdisp=10&possible1=Chuan](#)

[+C.Chang&possible1zone=article&OUTLOG=NO&viewabs=JESOAN&key=DISPLAY&d](#)  
[ocID=7&page=0&chapter=0](#)

(LEED Studies, Adsorption of Carbon Monoxide on the Tungsten (112) Face)

## Auger Spectroscopy

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4846849](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4846849)

(Intensity variations in Auger spectra caused by diffraction)

## Semiconductors

<http://scitation.aip.org/getabs/servlet/GetabsServlet?>

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(Anodic Oxide on GaAs: Quantitative Chemical Depth Profiles Obtained Using Auger Spectroscopy and Neutron Activation Analysis)

<http://www.sciencemag.org/content/245/4916/391.abstract>

(GaAs Clusters in the Quantum Size Regime: Growth on High Surface Area Silica by Molecular Beam Epitaxy)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4952743](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4952743)

(Chemical preparation of GaAs surfaces and their characterization by Auger electron and x-ray photoemission spectroscopies)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=5081499](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5081499)

(Co/GaAs interfacial reactions)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4859117](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4859117)

(Electronic passivation of GaAs surfaces through the formation of arsenic—sulfur bonds)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=5086280](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5086280)

(Enhanced electronic properties of GaAs surfaces chemically passivated by selenium reactions)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4856871](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4856871)

(Epitaxial growth of GaAs/NiAl/GaAs heterostructures)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=5101156](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5101156)

(Interdiffusions in thin-film Au on Pt on GaAs (100) studied with Auger spectroscopy)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4861404](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4861404)

(Ni-InP reaction: Formation of amorphous and crystalline ternary phases)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4856912](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4856912)

(NiAl/n-GaAs Schottky diodes: Barrier height enhancement by high-temperature annealing)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4956076](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4956076)

(Silicon-on-Sapphire Epitaxy by Vacuum Sublimation: LEED–Auger Studies and Electronic Properties of the Films)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4966237](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4966237)

(Structure and stability of passivating arsenic sulfide phases on GaAs surfaces)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4849348](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4849348)

(Thermal oxidation of hafnium silicide films on silicon)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=1478461](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=1478461)

(Transmission electron microscopy of cross sections of large scale integrated circuits)

[http://prl.aps.org/abstract/PRL/v57/i2/p249\\_1](http://prl.aps.org/abstract/PRL/v57/i2/p249_1)

(Unusually Low Surface-Recombination Velocity on Silicon and Germanium Surfaces)

[http://avspublications.org/jvsta/resource/1/jvtad6/v6/i3/p1456\\_s1?isAuthorized=no](http://avspublications.org/jvsta/resource/1/jvtad6/v6/i3/p1456_s1?isAuthorized=no)

(Studies of Co/Ga<sub>1-x</sub>Al<sub>x</sub>As interfaces fabricated in ultrahigh vacuum)

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<http://scitation.aip.org/getabs/servlet/GetabsServlet?>

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<http://scitation.aip.org/getabs/servlet/GetabsServlet?>

(The Growth and Characterization of Very Thin Silicon Dioxide Films)

<http://scitation.aip.org/getabs/servlet/GetabsServlet?>

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<http://scitation.aip.org/getabs/servlet/GetabsServlet?>

(Effect of Growth Parameters on the CVD of Boron Nitride and Phosphorus-Doped Boron Nitride)

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(Dry-etching process for the fabrication of optoelectronic gratings in III-V substrates)

## Superconductors

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4856026](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4856026)

(Pulsed laser etching of high T<sub>c</sub> superconducting films)

[http://jap.aip.org/resource/1/japiau/v61/i11/p5089\\_s1?isAuthorized=no](http://jap.aip.org/resource/1/japiau/v61/i11/p5089_s1?isAuthorized=no)

(Auger electron spectroscopy, transmission electron microscopy, and scanning electron microscopy studies of Nb/Al/Nb Josephson junction structures)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4857506](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4857506)

(As-deposited high T<sub>c</sub> and J<sub>c</sub> superconducting thin films made at low temperatures)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=5085237](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5085237)

(Doping mechanism in Bi(Pb)-Sr-Ca-Cu-O superconductors)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4857443](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4857443)

(Low-temperature preparation of high T<sub>c</sub> superconducting thin films)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4858680](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4858680)

(Microstructure of in situ epitaxially grown superconducting Y-Ba-Cu-O thin films)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4857684](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4857684)

(Nature of the pulsed laser process for the deposition of high T<sub>c</sub> superconducting thin films)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4858794](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4858794)

(Optical spectroscopy: An in situ diagnostic for pulsed laser deposition of high T<sub>c</sub> superconducting thin films)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4846419](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4846419)

(Plasma oxidation of aluminum film on GaAs—A study by Auger spectroscopy and transmission electron microscopy)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=4861876](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=4861876)

(Structural perfection of Y-Ba-Cu-O thin films controlled by the growth mechanism)

[http://ieeexplore.ieee.org/xpl/freeabs\\_all.jsp?arnumber=5082843](http://ieeexplore.ieee.org/xpl/freeabs_all.jsp?arnumber=5082843)

(Substrate effects on the properties of Y-Ba-Cu-O superconducting films prepared by laser deposition)

[http://apl.aip.org/resource/1/applab/v57/i17/p1814\\_s1?isAuthorized=no](http://apl.aip.org/resource/1/applab/v57/i17/p1814_s1?isAuthorized=no)

(Origin of surface roughness for c-axis oriented Y-Ba-Cu-O superconducting films)

## **Li Batteries**

[http://scitation.aip.org/getabs/servlet/GetabsServlet?  
prog=normal&id=JESOAN000139000007001845000001&idtype=cvips&gifs=yes&ref=n  
o](http://scitation.aip.org/getabs/servlet/GetabsServlet?prog=normal&id=JESOAN000139000007001845000001&idtype=cvips&gifs=yes&ref=no)

(Low Temperature LiMn<sub>2</sub>O<sub>4</sub> Spinel Films for Secondary Lithium Batteries)

## **Telephone Central Office**

[http://scitation.aip.org/vsearch/servlet/VerityServlet?  
KEY=FREESR&smode=results&maxdisp=10&possible1=Chuan  
+C.Chang&possible1zone=article&OUTLOG=NO&viewabs=JESOAN&key=DISPLAY&d  
ocID=15&page=2&chapter=0](http://scitation.aip.org/vsearch/servlet/VerityServlet?KEY=FREESR&smode=results&maxdisp=10&possible1=Chuan+C.Chang&possible1zone=article&OUTLOG=NO&viewabs=JESOAN&key=DISPLAY&docID=15&page=2&chapter=0)

(Monitoring of In Situ Corrosion Rates in a Telephone Switching Office in Burbank, California)